•	Se	earch Notes					

Application/Control No.	Applicant(s)/Patent Reexamination	under :
10/662,508	TAKAYAMA ET AL	••
Examiner	Art Unit	
Thao X. Le	2814	

SEARCHED				
Class	Subclass	Date	Examiner	
257	347,40,59 71,351 357,347 365	1/31/2005	TL	
257	79-82	1/31/2005	TL	
2578	57-59	1/31/2005	TL	
Update	search	6/17/2005	TL	
Upadte	search	11/18/2005	TL	
313	504-506	11/18/2005	TL	
Upadte	Search	3/29/2006	TL	
Update	Search	8/31/2006	TL	

INTERFERENCE SEARCHED				
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see print out	1/31/2005	TL
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